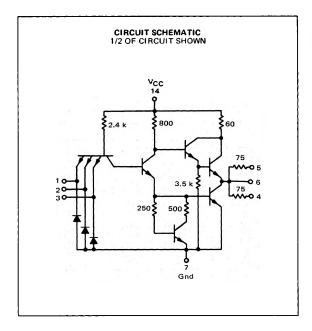
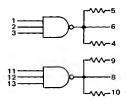
MC3100/MC3000 series

MC3129F · MC3029F MC3129L · MC3029L,P



This device is a dual 3-input/3-output series-terminated NAND line driver that minimizes switching transients on long lines by approximating line impedance. Two outputs are provided through 75-ohm resistors for use when driving 93 to 120-ohm lines. These outputs should be paralleled when driving 50 to 93-ohm lines. In addition, an output is provided directly at the gate output node for driving adjacent gates.



Positive Logic: 4, 5, 6 = $1 \cdot 2 \cdot 3$

Negative Logic: 4, 5, 6 = 1 + 2 + 3

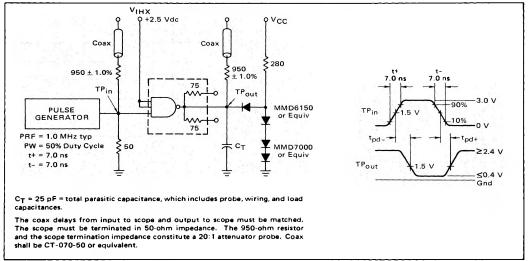
Input Loading Factor = 1

Output Loading Factor, Direct Output (Pins 6 and 8) = 8 Minus The Number of Resistor-Terminated Outputs Being Used.

Output Loading Factor, Resistors (Pins 4, 5, 9 and 10) = 1

Total Power Dissipation = 44 mW typ/pkg Propagation Delay Time = 6.0 ns typ

SWITCHING TIME TEST CIRCUIT AND WAVEFORMS



V_c

TEST CURRENT/VOLTAGE VALUES

OHA OHB

© Test

Temperature

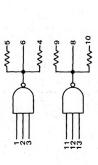
-5°C

29 +25°C

+125°C

ELECTRICAL CHARACTERISTICS

Test procedures are shown for only one line driver. The other line driver is tested in the same manner. Further, test procedures are shown for only one input of the line driver under test. To complete testing sequence through remaining inputs.



ic Symbol Und Und In											-	_	17.57+	19	2.0	0.2		1.0	;	7:	2	1.1	5. 8.	4	+	4.0	0.1	0.0	+	9. 59	2.5	
ic Symbol Unduling Phi Phi												1	75.0	16	2.0	_								L						-		
ic Symbol Int IF It Age BV in VD	12		-									-	17.51			-	-1.8	-0.1	-0.1			0.9 1.8 0.4	1.8 0.	_	2.5	4.0	,	2.0	4.75	5.25		
ic Symbol IF II IR IR AD VD	12		MC312	MC3129 Test	Limits				MC302	MC3029 Test Limits	Limits								TEST	CURR	NT / V	TAGE	APPLIE	50 TO P	TEST CURRENT / VOLTAGE APPLIED TO PINS LISTED BELOW	BELOW:						
ic Symbol IF II IR IR IR VD	ч	-55°C	+25°C	ي ر	+125°C	2,€	ე,0	u	+25°C	ړ	+75°C	2	1	-		1	-		-		+	+	+	-	-	1		T	-		T	
		Max	Win	Min Max	Min	Max	Win	Max	Wij	Max	Wij	Max	±	4	8	20	4	ě	ě	_5	٥	^ >"	<u>~</u>	>"	~	¥.	V _{mex}	8	V _{CC1}	V _{CCH}	VIHX	Gnd
tage BV _{in}	•	-2.0	16	-2.0	1.	-2.0	•	-2.0		-2.0		-2.0 n	mAdc								1.		-	1		2,3				14		*4
tage BV _{in}		20		20	i	20		20		20	•	20	пАдс			•			-				,	,	_					4		2, 3, 7*
a _n		,	5.5	1		,			5.5				Vdc				Ÿ			1										14		2,3,7
	-	•	•	-1.5			1,			-1.5			Vdc				٠,		1		-								14			44
Voltage Vol.1 6	-	0.4		4.0		9.4		4.0		4.0	-	4.0	Vdc		s.	-							-		-	2,3			2			**
Vol. 2 5		0.5		0.5		0.5		0.5		0.5		0.5	Vdc		6		:					,	-		-	2,3			11			7.4
у но в	4.		2.4		4.2		2.5		2.5		5.5		Vdc				9		s		,		-			2,3			14			**
Short-Circuit I _{SC} 6	-40	-100	-40	-100		-100	-40	-100	-40	-100	-40	-100	mAdc																	14	1	1, 2, 3, 6, 7 *
Total Device) (Total Device) Maximum Power I max 14		1 10		21					•	. 21		,	mAdc									- 1					14				1	1, 2, 3, 7, 11, 12, 13
Power Supply Drain IpDH 14	1.	19		19		19		19		19		19 n	mAde	,									-	-	- 11,	1, 2, 3,	, -			14		7
¹ PDL 14	-	9.6		9.6		9.6		9.6		9.6		9.6 n	mAdc																	14		1, 2, 3, 7, 11, 12, 13
Switching Parameters Turn-On Delay t _{od} 1,6			4.11	01			100			91			8	Pulse -	e Pelse						-	-	-	-				14	,	•	8,3	4.
Turn-Off Delay tpd+ 1,6	-			9		1	1.			9	1.		su	-	9	1		1.			1.	1.	1:	-	ļ.,			41		ļ.	2,3	1*

*Since this is an inverting gate, power drain is minimized by grounding the inputs to gates not under test.